

<b>Notice of References Cited</b>	Application/Control No. 10/586,822		Applicant(s)/Patent Under Reexamination CHENG ET AL.	
	Examiner Desta L. Yebassa		Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,593,687	01-1997	Rossling et al.	424/450
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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*	N	WO 00/56282	09-2000	US	Alpar et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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